Volume 96, Number 6, November–December 1991
Journal of Research of the National Institute of Standards and Technology

Subject Index to Volume 96

Numbers in parenthesis after the page number are the issue numbers

No. 1 January-February
No. 2 March-April
No. 3 May-June
No. 4 July-August
No. 5 September-October
No. 6 November-December

A

acid rain ..... 541(5)
acoustic emission ..... 345(3)
acrylonitrile-butadiene-styrene ..... 741(6)
activity coefficient ..... 757(6)
advanced technology ..... 605(5)
aerosol generator ..... 147(2)
amino acid ..... 757(6)
analysis of gases ..... 541(5)
application portability ..... 767(6)
argon ..... 247(3)
asymmetric synthesis ..... 1(1)
atomic weights ..... 617(5)
atomizers ..... 147(2)
automated testing ..... 291(3)

B

bidirectional reflectance distribution function (BRDF) ..... 215(2)
bidirectional scattering distribution function (BSDF) ..... 215(2)
bidirectional transmittance distribution function (BTDF) ..... 215(2)
branched polymers ..... 177(2)

C

Ca flux ..... 593(5)
calorimeter ..... 725(6)
carbon dioxide ..... 547(5)
causal boundary roots ..... 333(3)
causal time series ..... 345(3)
cell constant ..... 191(2)
ceramic materials ..... 115(1)
ceramic matrix composites ..... 493(4)
chain branching ..... 177(2)
chiral auxiliaries ..... 1(1)
clamp overshoot ..... 291(3)
combustion ..... 741(6)
combustion products ..... 741(6)
compressed gas ..... 541(5)
computer simulation ..... 391(4), 593(5)
condensation nuclei counters ..... 147(2)
conductance ..... 191(2)
conformance tests ..... 767(6)
cooperative agreements ..... 605(5)
coulometry ..... 541(5), 547(5)
coupled dissolution-diffusion ..... 593(5)
critical current ..... 703(6)
cross-cut algorithm ..... 345(3)
crowbar ..... 291(3)
crystal growth ..... 305(3)
cup furnace ..... 741(6)
current efficiency ..... 547(5)
cylinder gases ..... 547(5)

D

data administration ..... 633(5)
data management ..... 633(5)
deadweight machines ..... 529(5)
deconvolution ..... 345(3)
demal ..... 191(2)
demineralization ..... 203(2)
dental caries ..... 203(2), 593(5)
difference sets ..... 577(5)
diffraction ..... 305(3)
diffuse reflectance ..... 215(2)
digital image analysis ..... 203(2)

E

efficiency curve ..... 693(6)
electrical mobility ..... 147(2)
electrolytic conductivity ..... 191(2)
electron microscopy ..... 551(5), 669(6)
electronic ceramics ..... 115(1)
electronic circuit ..... 703(6)
emf ..... 757(6)
enantiomers ..... 1(1)
experimental design ..... 613(5)

F

fast switching ..... 291(3)
FFT deconvolution ..... 345(3)
fibers ..... 493(4)
fire models ..... 411(4)
fire tests ..... 411(4)
force measurements ..... 529(5)
force standards ..... 529(5)
force transducers ..... 529(5)
fractional factorial plans ..... 577(5)

G

gallium arsenide ..... 305(3)
Gaussian deconvolution ..... 345(3)
gel permeation chromatography ..... 177(2)
generic technology ..... 605(5)
germanium detectors ..... 225(2)
glass ..... 493(4)
Gram-Schmidt algorithm ..... 333(3)
group divisible design ..... 613(5)

H

heat capacity ..... 247(3), 725(6)
heterodyne ..... 143(2)
high frequency ..... 143(2)
high pressure ..... 725(6)
high-T_c ..... 703(6)
higher order modes ..... 565(5)
hydroxyapatite ..... 593(5)

I

induced junction photodiode ..... 471(4)
industrial competitiveness ..... 605(5)
inhalation ..... 741(6)
instrument signature ..... 215(2)
internal quantum-efficiency ..... 463(4), 481(4)
international intercomparison ..... 225(2)
interoperability ..... 767(6)
inverse scattering problem ..... 215(2)
inversion layer photodiode ..... 471(4)
iron in biological systems ..... 1(1)
iron-carbene complexes ..... 1(1)
irradiance ..... 143(2)
isochoric ..... 725(6)
isotope abundances ..... 617(5)
isotope reference materials ..... 617(5)
isotopic mass spectrometry ..... 617(5)

L

large area source ..... 693(6)
lead tin telluride ..... 305(3)
light scattering ..... 177(2), 669(6)
low-T_c ..... 703(6)

M

mercuric iodide ..... 305(3)
microgravity ..... 305(3), 669(6)
micrometrology ..... 669(6)
microradiography ..... 203(2)
microscopy ..... 669(6)
microspheres ..... 551(5), 669(6)
microwave ..... 565(5)
molal ..... 191(2)
monoethanolamine ..... 547(5)

N

national laboratories ..... 647(6)
national standards ..... 225(2)
nitrogen ..... 247(3), 725(6)
N,N-dimethylformamide ..... 547(5)
numerical modeling ..... 471(4)
numerical simulation ..... 471(4)

O

open systems ..... 763(6), 767(6)
Open Systems Interconnection (OSI) ..... 763(6), 767(6)
optical communications ..... 225(2)
optical detectors ..... 225(2)
optical fiber measurements ..... 231(2)
optical microscopy ..... 551(5)
optical power ..... 225(2)
organoiron complexes ..... 1(1)
orthogonal arrays ..... 577(5)
orthogonal distance regression ..... 565(5)
oxide-bias experiment ..... 471(4)

P

P flux ..... 593(5)
partially balanced designs ..... 613(5)
particle size ..... 147(2), 551(5)
particle sizing ..... 669(6)
particles ..... 669(6)
permeability ..... 565(5)

permittivity ..... 565(5)
permselective diffusion ..... 593(5)
photodiode ..... 143(2), 481(4)
photodiode modeling ..... 463(4)
plutonium-238 ..... 693(6)
polarization ..... 215(2)
polymer chain branching ..... 177(2)
polymer characterization ..... 503(4), 623(5)
polymer composites ..... 623(5)
polymer molecular weight ..... 177(2)
polymer processing ..... 503(4)
polymer technology ..... 623(5)
polystyrene ..... 551(5)
polystyrene latex spheres ..... 147(2)
polystyrene spheres ..... 669(6)
potassium chloride ..... 191(2)
primary mode ..... 565(5)
primary standards ..... 191(2)
Prony's method ..... 333(3)
proportional counting ..... 693(6)
protection circuit ..... 291(3)

Q

quality control ..... 271(3)
quantum efficiency ..... 471(4)

R

radiation correction ..... 247(3)
radiometry ..... 647(6)
reference materials ..... 669(6)
reflectometry ..... 231(2)
remineralization ..... 203(2)
resistance ..... 191(2)
reverse-bias ..... 291(3)
rheological measurements ..... 503(4)
root projection ..... 333(3), 345(3)
roughness ..... 271(3)
roughness average ..... 271(3)

S

safe-operating area ..... 291(3)
salt interaction ..... 757(6)
scattering matrix ..... 565(5)
scattering theory ..... 215(2)
second breakdown ..... 291(3)
signal processing ..... 333(3), 345(3)
silicon ..... 481(4), 617(5)
silicon photodiodes ..... 463(4)
silicon tetrafluoride ..... 617(5)
singular value decomposition ..... 345(3)
size exclusion chromatography ..... 177(2)
sodium chloride ..... 757(6)
specific conductance ..... 191(2)
spectral irradiance ..... 647(6)
specular reflectance ..... 215(2)
spherical far fields ..... 391(4)
spherical near fields ..... 391(4)
Standard Reference Material (SRM) ..... 271(3), 551(5), 741(6)
standards ..... 271(3), 669(6), 703(6), 763(6), 767(6)
standards for data administration ..... 633(5)
star polymers ..... 177(2)
star-branched polymers ..... 177(2)
step height ..... 271(3)
stereoselective reactions ..... 1(1)
stray light ..... 215(2)
stylus ..... 271(3)
sulfur dioxide ..... 541(5)
superconductor ..... 703(6)
superconductor simulator ..... 703(6)
surface finish ..... 215(2)
synchrotron ..... 305(3)

T

Taguchi's methods ..... 577(5)
tensile strength ..... 493(4)
thermal conductivity ..... 247(3)
thermal diffusivity ..... 247(3)
time series ..... 333(3), 345(3)
toluene ..... 247(3)
tooth mineral ..... 203(2)
topography ..... 305(3)
toxicity tests ..... 741(6)
transducer calibration ..... 345(3)
transient hot-wire ..... 247(3)
transistor ..... 291(3)
triglycine sulfate ..... 305(3)
tungsten-halogen lamps ..... 647(6)

U

x ray ..... 693(6)

V

vapor ..... 725(6)
voltage-current characteristic ..... 703(6)

Z

Z transforms ..... 333(3)

Volume 96, Number 6, November–December 1991
Journal of Research of the National Institute of Standards and Technology

Author Index to Volume 96

Numbers in parenthesis after the volume number are the issue numbers

No. 1 January-February
No. 2 March-April
No. 3 May-June
No. 4 July-August
No. 5 September-October
No. 6 November-December

A

Asmail, C.

Bidirectional Scattering Distribution Function (BSDF): A Systematized Bibliography. Asmail, C. **96**(*2*), 215 (1991).

B

Babrauskas, V.

Data for Room Fire Model Comparisons. Peacock, R. D., Davis, S., and Babrauskas, V. **96**(*4*), 411 (1991).

Baker-Jarvis, J.

Optimization Techniques for Permittivity and Permeability Determination. Domich, P. D., Baker-Jarvis, J., and Geyer, R. G. **96**(*5*), 565 (1991).

Batra, A.

High Resolution Synchrotron X-Radiation Diffraction Imaging of Crystals Grown in Microgravity and Closely Related Terrestrial Crystals. Steiner, B., Dobbyn, R. C., Black, D., Burdette, H., Kuriyama, M., Spal, R., van den Berg, L., Fripp, A., Simchick, R., Lal, R. B., Batra, A., Matthiesen, D., and Ditchek, B. **96**(*3*), 305 (1991).

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Berning, D.

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Bryner, N. P.

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C

Carey, C. M.

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Chandler-Horowitz, D.

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Chang, S. S.

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D

Davis, S.

Data for Room Fire Model Comparisons. Peacock, R. D., Davis, S., and Babrauskas, V. **96**(*4*), 411 (1991).

Day, G. W.

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F

Fatiadi, A. J.

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Feng, D.

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G

Gallawa, R. L.

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Geyer, R. G.

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H

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Hodge, P. A.

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J

Jackson, J. K.

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Jordan, T. H.

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K

Kacker, R. N.

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L

Lagergren, E. S.

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Li, X.

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M

Magee, J. W.

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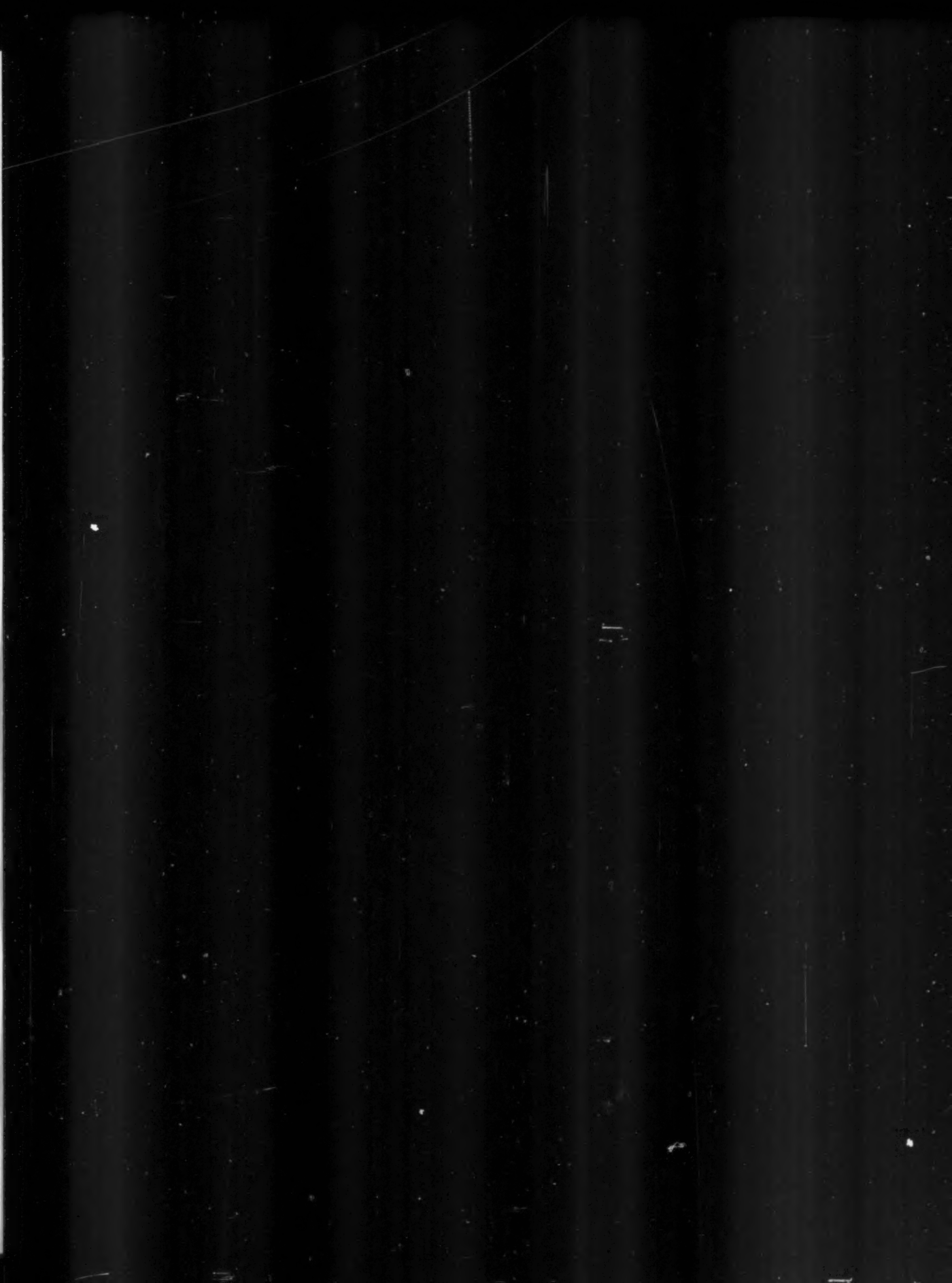
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